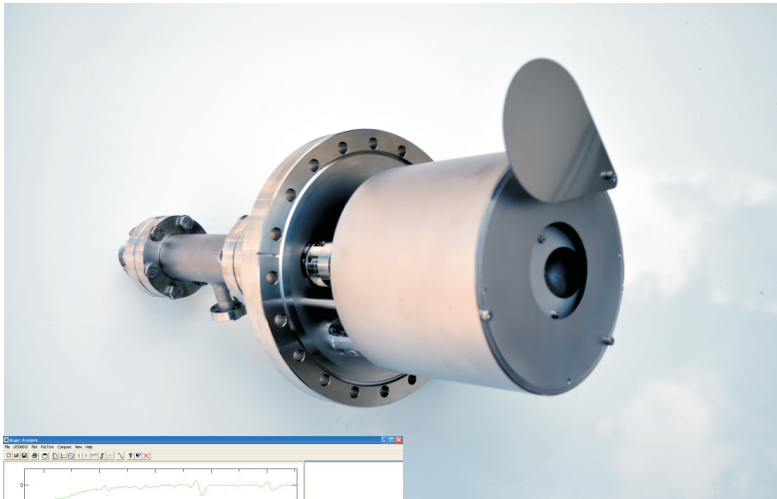


Large Area Auger Profiler

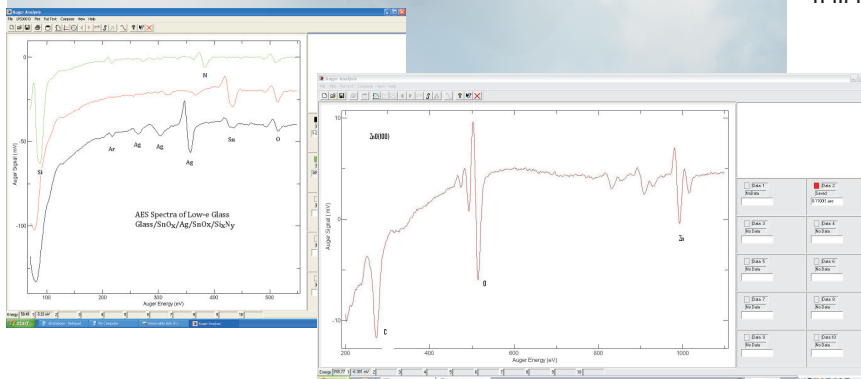
MODEL LADP800

Thin Film Elemental Composition at Different Depth

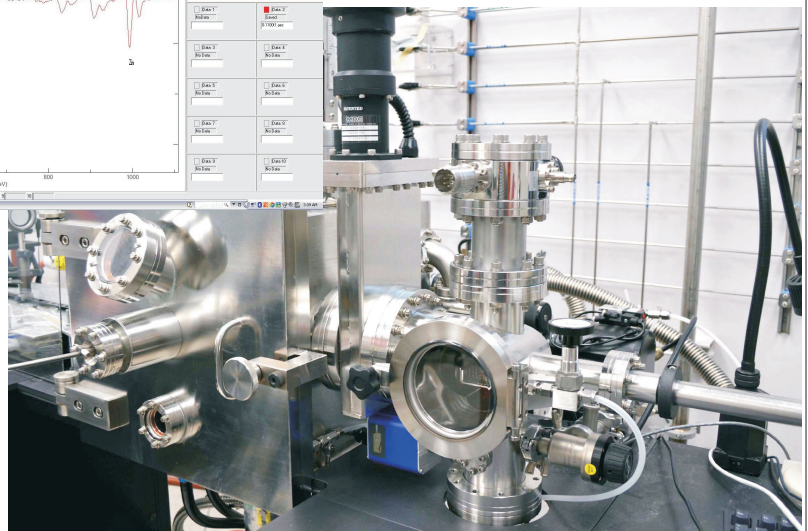


Model LADP800 is the compact instrument to measure elemental surface composition of thin films using Auger electron spectroscopy and Argon ion bombardment to obtain composition v.s depth.

In addition, the instrument can integrate gas emission analysis from thin film.



Customized side UHV attachment to fit most of the vacuum deposition chambers.



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